

Substitute for form 1449A/B/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)			<b>Complete if Known</b>		
			Application Number	10/009,280	
			Filing Date	<del>December 7, 2001</del> 5/13/2002	
			First Named Inventor	Read	
			Group Art Unit	Unassigned 2881	
Examiner Name	Unassigned Chris Kalivoda				
Sheet	1	of	1	Attorney Docket Number	214764

U.S. PATENT DOCUMENTS						
Examiner Initials	Doc. No.	U.S. Patent Document		Name of Patentee or Applicant	Date of Publication	Filing Date If Appropriate
		Application or Patent Number	Kind Code			
CMK	AA	3,735,128		Palmberg	5/22/1973	—
CMK	AB	3,783,280		Watson	1/1/1974	—
CMK	AC	4,367,406		Franzen et al.	1/4/1983	—
CMK	AD	4,593,196		Yates	6/3/1986	—
CMK	AE	5,032,724		Gerlach et al.	7/16/1991	—
CMK	AF	5,594,244		Pruett	1/14/1997	—

FOREIGN PATENT DOCUMENTS								
Examiner Initials	Doc. No.	Foreign Patent Document			Name of Patentee or Applicant	Date of Publication	Translation	
		Office	Application or Patent Number	Kind Code			Yes	No**
CMK	AG	GB	1,387,173		Hitachi Limited	3/12/1975		X
CMK	AH	DE	2648-466	A1	Hahn-Meitner-Institut	10/26/1976	Ab	
CMK	AI	EP	0 255 981	A1	Kratos Analytical Limited	2/17/1988		X
CMK	AJ	DE	4341144	A1	Staib Instr. GmbH	6/8/1995	Ab	
CMK	AK	WO	99/35668	A2	University of York	7/15/1999		X

OTHER - NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Doc. No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number (s), publisher, city and/or country where published.	Translation	
			Yes	No**
CMK	AL	Bosch et al., "A simultaneous angle-resolved photoelectron spectrometer," <i>J. Phys. E:Sci. Instrum.</i> , 17, pp. 1187-1192 (1984)		
CMK	AM	Allenspach et al., "Spin-polarized Auger-electron spectroscopy," <i>Physical Review B</i> , 35:10, pp. 4801-4809 (1987)		
CMK	AO	Jacka et al., "A fast, parallel acquisition, electron energy analyzer: The hyperbolic field analyzer," <i>Rev. Sci. Instrum.</i> , 70:5, pp. 2282-2287 (1999)		
CMK	AP	Risley, "Design Parameters for the Cylindrical Mirror Energy Analyzer," <i>Rev. Sci. Instrum.</i> , 43:1, pp. 95-103 (1972)		
CMK	AQ	Roy et al., "Design of electron spectrometers," <i>Rep. Prog. Phys.</i> , 53, pp. 1621-1674 (1990)		

Examiner Signature	Chris Kalivoda	Date Considered	July 17, 2003
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\* A concise statement of relevance is being submitted in lieu of a translation. 37 CFR 1.98(a)(3).  
 + An English-language equivalent/patent, or an English-language abstract, or an English-language version of the search report or action by a foreign patent office in a counterpart foreign application indicating the degree of relevance found by the foreign office is being submitted in lieu of a concise explanation of relevance under 37 CFR 1.98(a)(3).